論 文 内 容 要 旨

報告番号	甲 先	第	-4-5· 5 -	- 号	氏	名	IMRAN BIN SUTAN CHAIRUL
Fabrication of Transparent ITO/GTO Bilayer Thin Films using a Facing Target DC Magnetron Sputtering							
学位論文題	ヨ (対向ター	(対向ターゲット式DCマグネトロンスパッタ法を用いた透明ITO/GTO二層膜の作製)					

内容要旨

Due to the scarcity of Indium (In) in the future, efforts have been made to fabricate In-free semiconductors such as Ga-Sn-O (GTO) thin films via chemical vapour deposition, RF magnetron sputtering, and DC magnetron sputtering. However, an amorphous GTO fabricated by using DC magnetron sputtering is focused on a specific Ga:Sn ratio, and this opens avenues for further research using other Ga:Sn ratios. Hence, this study fabricated transparent diodes by layering a GTO thin film onto an In2O3:Sn (ITO) thin film using a facing targeted DC magnetron cosputtering method. Ga:Sn ratio was adjusted by varying the current applied to the targets and the number of Ga2O3 pellets. Following that, the composition, phase, and optical transmittance of the GTO thin films were characterized. The current-voltage (I-V) characteristics of the fabricated ITO/GTO bilayer diode thin films were also determined. Results show that when a GTO film containing approximately 25 mol% Ga was deposited on the surface of the conductive ITO film at room temperature, a diode bilayer film was obtained. The bilayer film exhibited rectification characteristics of approximately 0 and 3.8 μ A/V when negative and positive voltages were applied, respectively. However, the rectification characteristics increased up to 68.3 μ A/V in the positive voltage region after annealing at 200 °C.